## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHANG ET AL. | Examiner | Art Unit | Joseph Nguyen | 2815 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0143772	07-2003	Chen, Tzer-Perng	438/47
	В	US-6,712,478	03-2004	Sheu et al.	257/79
	С	US-			
	D	US-			
	Ε	US-			
	F	US-		•	
	G	US-			
	Н	US-			
	ı	US-		·	
	J	US-			
	К	US-			
	L	US-	·		
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N						
	0						
	Р				`		
	Q	,					
	R						
	s						
	Т						

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	>	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.